



APPENDIX D: SYSTEM CERTIFICATE & CALIBRATION

D1: PHANTOM

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Certificate of Conformity / First Article Inspection

Item	Oval Flat Phantom ELI 4.0
Type No	QD OVA 001 B
Series No	1003 and higher
Manufacturer	SPEAG Zeughausstrasse 43 CH-8004 Zürich Switzerland

Tests

Complete tests were made on the prototype units QD OVA 001 AA 1001, QD OVA 001 AB 1002, pre-series units QD OVA 001 BA 1003-1005 as well as on the series units QD OVA 001 BB, 1006 ff.

Test	Requirement	Details	Units tested
Dimensions	Compliant with the standard IEC 62209 – 2 [1] requirements	Dimensions of bottom for 300 MHz – 6 GHz: longitudinal = 600 mm (max. dimension) width = 400 mm (min dimension) depth = 190 mm Shape: ellipse	Prototypes, Samples
Material thickness	Compliant with the standard IEC 62209 – 2 [1] requirements	Bottom plate: 2.0mm +/- 0.2mm	Prototypes, All items
Material parameters	Dielectric parameters for required frequencies	300 MHz – 6 GHz Rel. permittivity = 4 +/-1, Loss tangent ≤ 0.05	Material sample
Material resistivity	The material has been tested to be compatible with the liquids defined in the standards if handled and cleaned according to the instructions. Observe Technical Note for material compatibility.	DEGMBE based simulating liquids	Equivalent phantoms, Material sample
Sagging	Compliant with the requirements according to the standard. Sagging of the flat section when filled with tissue simulating liquid	< 1% typical < 0.8% if filled with 155mm of HSL900 and without DUT below	Prototypes, Sample testing

Standards

- [1] IEC 62209 – 2, Draft Version 0.9, "Evaluation of Human Exposure to Radio Frequency Fields from Handheld and Body-Mounted Wireless Communication Devices in the Frequency Range of 30 MHz to 6 GHz: Human models, Instrumentation and Procedures Part 2: Procedure to determine the Specific Absorption Rate (SAR) for ... including accessories and multiple transmitters", December 2004

Conformity

Based on the sample tests above, we certify that this item is in compliance with the standard [1].

Date 07.07.2005

Signature / Stamp

s p e a g

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A D T

D2: DOSIMETRIC E-FIELD PROBE



Accredited by the Swiss Accreditation Service (SAS)
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **BV-ADT (Auden)**

Certificate No: **EX3-3590_Mar10**

CALIBRATION CERTIFICATE

Object **EX3DV4 - SN:3590**

Calibration procedure(s) **QA CAL-01.v6, QA CAL-14.v3, QA CAL-23.v3 and QA CAL-25.v2
Calibration procedure for dosimetric E-field probes**

Calibration date: **March 25, 2010**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	1-Apr-09 (No. 217-01030)	Apr-10
Power sensor E4412A	MY41495277	1-Apr-09 (No. 217-01030)	Apr-10
Power sensor E4412A	MY41498087	1-Apr-09 (No. 217-01030)	Apr-10
Reference 3 dB Attenuator	SN: S5054 (3c)	31-Mar-09 (No. 217-01026)	Mar-10
Reference 20 dB Attenuator	SN: S5086 (20b)	31-Mar-09 (No. 217-01028)	Mar-10
Reference 30 dB Attenuator	SN: S5129 (30b)	31-Mar-09 (No. 217-01027)	Mar-10
Reference Probe ES3DV2	SN: 3013	30-Dec-09 (No. ES3-3013_Dec09)	Dec-10
DAE4	SN: 660	29-Sep-09 (No. DAE4-660_Sep09)	Sep-10

Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Oct-09)	In house check: Oct-11
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-09)	In house check: Oct10

	Name	Function	Signature
Calibrated by:	Katja Pokovic	Technical Manager	
Approved by:	Niels Kuster	Quality Manager	

Issued: March 25, 2010

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.



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Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C	modulation dependent linearization parameters
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E^2 -field uncertainty inside TSL (see below *ConvF*).
- NORM(f)_{x,y,z}** = NORM_{x,y,z} * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}; A, B, C** are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV4

SN:3590

Manufactured:	March 23, 2009
Last calibrated:	April 28, 2009
Recalibrated:	March 25, 2010

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

DASY - Parameters of Probe: EX3DV4 SN:3590**Basic Calibration Parameters**

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu\text{V}/(\text{V}/\text{m})^2$) ^A	0.49	0.49	0.50	± 10.1%
DCP (mV) ^B	88.1	87.5	87.6	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300	± 1.5%
			Y	0.00	0.00	1.00	300	
			Z	0.00	0.00	1.00	300	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

DASY - Parameters of Probe: EX3DV4 SN:3590

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	41.5 ± 5%	0.97 ± 5%	10.25	10.25	10.25	0.74	0.61 ± 11.0%
1750	± 50 / ± 100	40.1 ± 5%	1.37 ± 5%	8.89	8.89	8.89	0.76	0.58 ± 11.0%
1950	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	8.33	8.33	8.33	0.62	0.64 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	7.90	7.90	7.90	0.36	0.84 ± 11.0%
2600	± 50 / ± 100	39.0 ± 5%	1.96 ± 5%	7.79	7.79	7.79	0.19	1.32 ± 11.0%
5200	± 50 / ± 100	36.0 ± 5%	4.66 ± 5%	5.30	5.30	5.30	0.40	1.90 ± 13.1%
5300	± 50 / ± 100	35.9 ± 5%	4.76 ± 5%	4.92	4.92	4.92	0.45	1.90 ± 13.1%
5500	± 50 / ± 100	35.6 ± 5%	4.96 ± 5%	4.93	4.93	4.93	0.45	1.90 ± 13.1%
5600	± 50 / ± 100	35.5 ± 5%	5.07 ± 5%	4.63	4.63	4.63	0.50	1.90 ± 13.1%
5800	± 50 / ± 100	35.3 ± 5%	5.27 ± 5%	4.54	4.54	4.54	0.50	1.90 ± 13.1%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

DASY - Parameters of Probe: EX3DV4 SN:3590

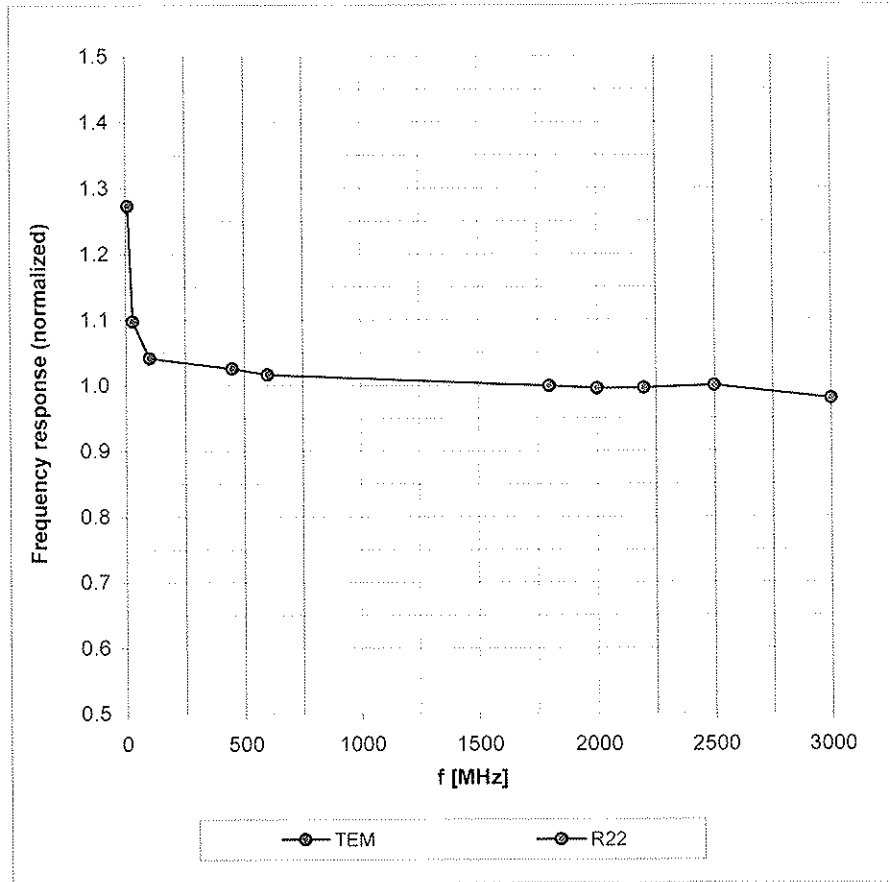
Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	55.0 ± 5%	1.05 ± 5%	10.20	10.20	10.20	0.60	0.71 ± 11.0%
1750	± 50 / ± 100	53.4 ± 5%	1.49 ± 5%	8.69	8.69	8.69	0.79	0.58 ± 11.0%
1950	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	8.61	8.61	8.61	0.40	0.80 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	8.20	8.20	8.20	0.28	1.02 ± 11.0%
2600	± 50 / ± 100	52.5 ± 5%	2.16 ± 5%	8.04	8.04	8.04	0.21	1.25 ± 11.0%
5200	± 50 / ± 100	49.0 ± 5%	5.30 ± 5%	4.80	4.80	4.80	0.53	1.95 ± 13.1%
5300	± 50 / ± 100	48.5 ± 5%	5.42 ± 5%	4.50	4.50	4.50	0.53	1.95 ± 13.1%
5500	± 50 / ± 100	48.6 ± 5%	5.65 ± 5%	4.32	4.32	4.32	0.55	1.95 ± 13.1%
5600	± 50 / ± 100	48.5 ± 5%	5.77 ± 5%	4.16	4.16	4.16	0.50	1.95 ± 13.1%
5800	± 50 / ± 100	48.2 ± 5%	6.00 ± 5%	4.41	4.41	4.41	0.60	1.95 ± 13.1%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

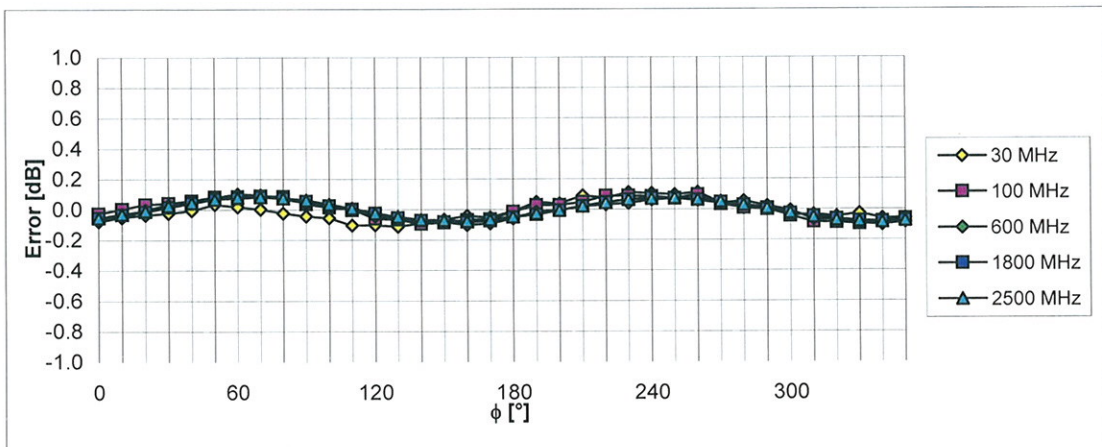
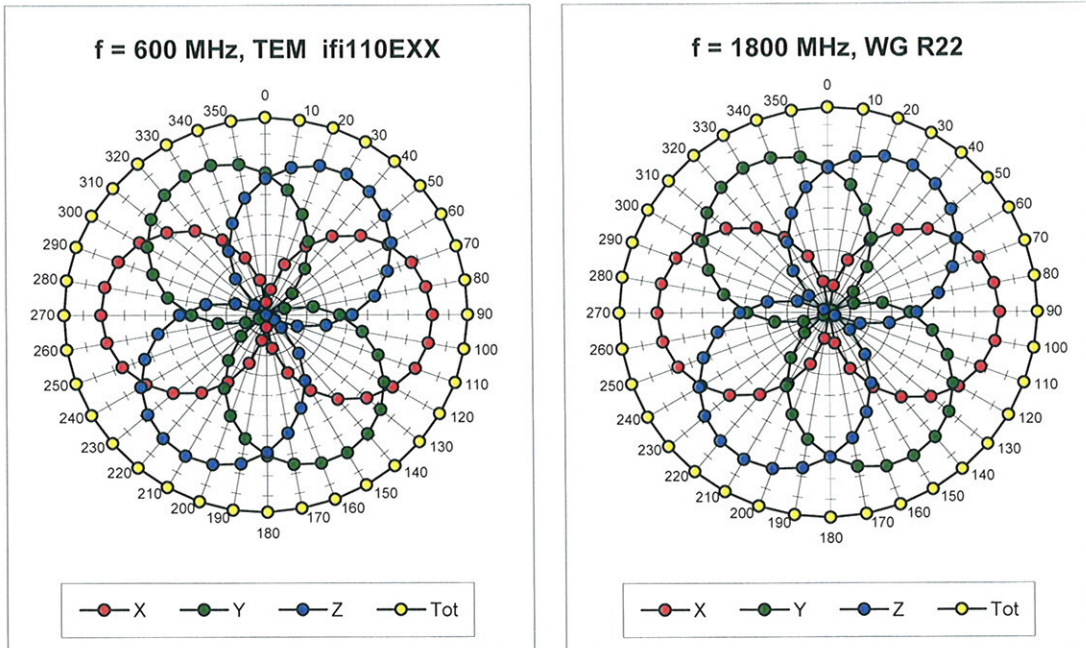
Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



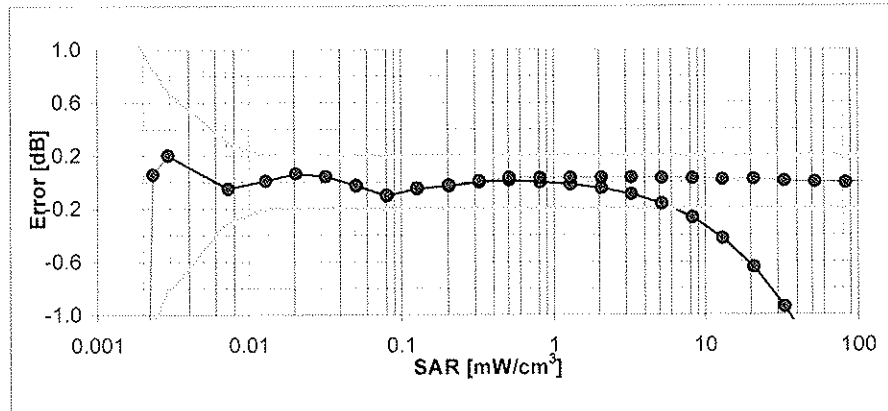
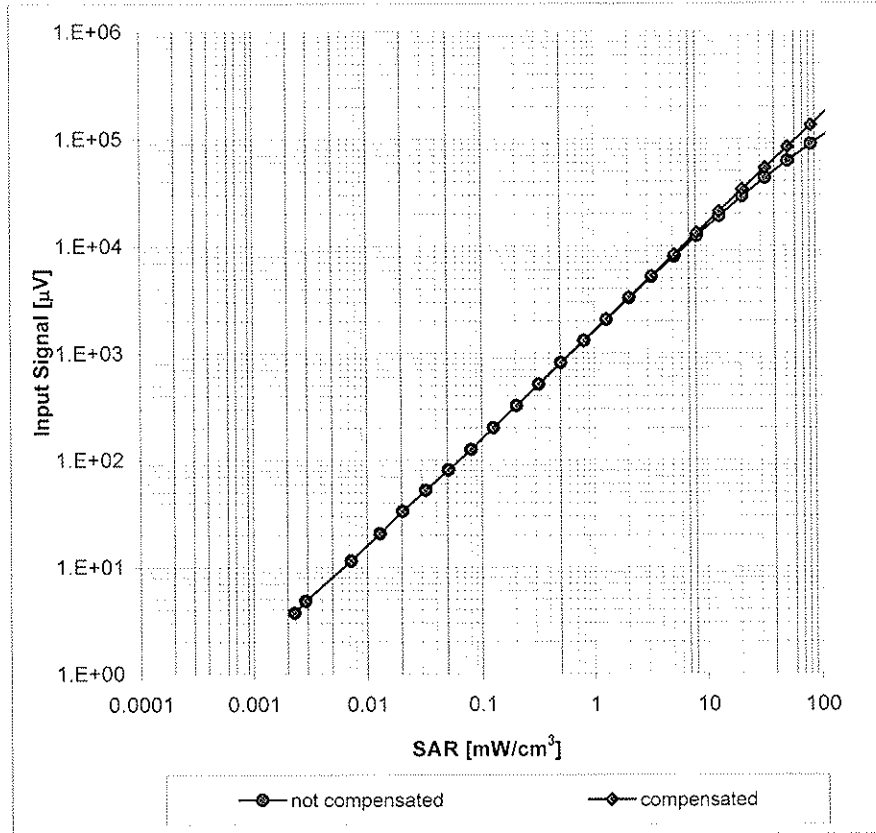
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

Receiving Pattern (ϕ), $\vartheta = 0^\circ$



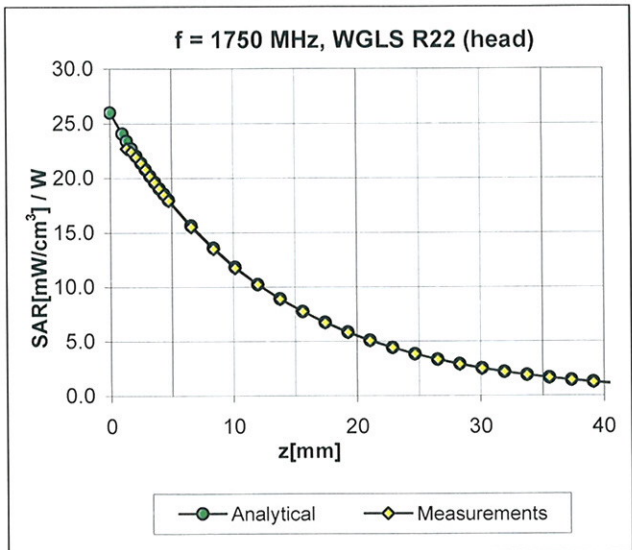
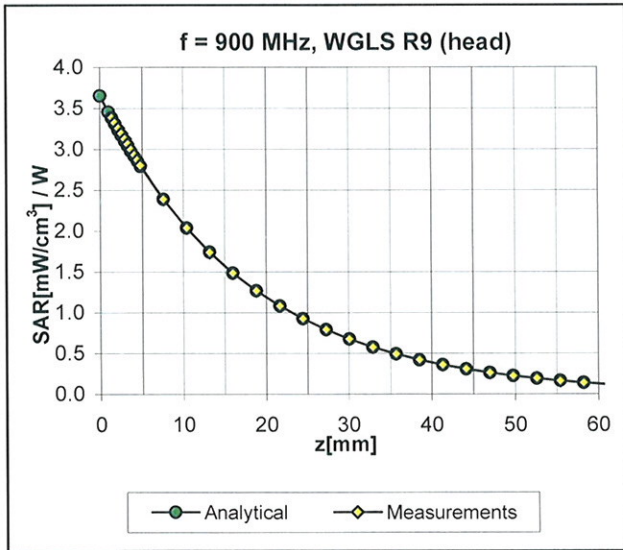
Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ (k=2)

Dynamic Range $f(\text{SAR}_{\text{head}})$ (Waveguide R22, $f = 1800 \text{ MHz}$)



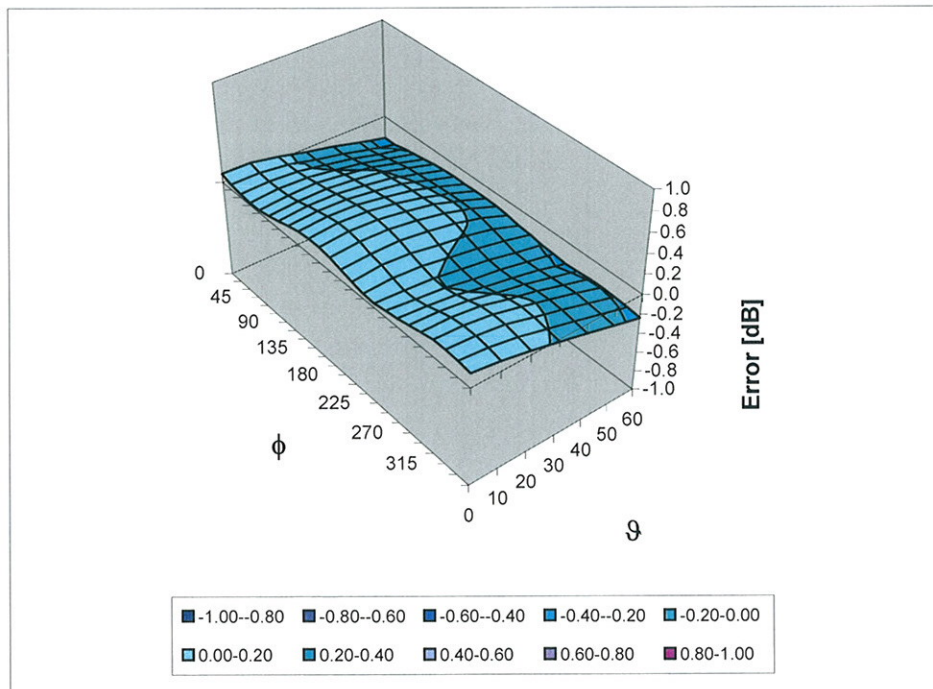
Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

Conversion Factor Assessment



Deviation from Isotropy in HSL

Error (ϕ, ϑ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ (k=2)

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	Not applicable
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	9 mm
Tip Diameter	2.5 mm
Probe Tip to Sensor X Calibration Point	1 mm
Probe Tip to Sensor Y Calibration Point	1 mm
Probe Tip to Sensor Z Calibration Point	1 mm
Recommended Measurement Distance from Surface	2 mm